CORNING



Corning Tropel Semiconductor Metrology

Corning Tropel manufactures a complete line of non-contact metrology instruments for the semiconductor industry. Each system measures surface form with sub-micron accuracy in seconds. The data acquisition and analysis provides complete surface characterization in easy to read graphical output. Designed to operate in a wide range of environments; from the shop floor to the R&D lab. Whatever your application you'll find a system that is right for you.

TROPEL®

METROLOGY INSTRUMENTS

Tropel® FlatMaster® Systems

Part sizes from 5 mm to 200 mm
The ideal tool for measuring pellicle frames

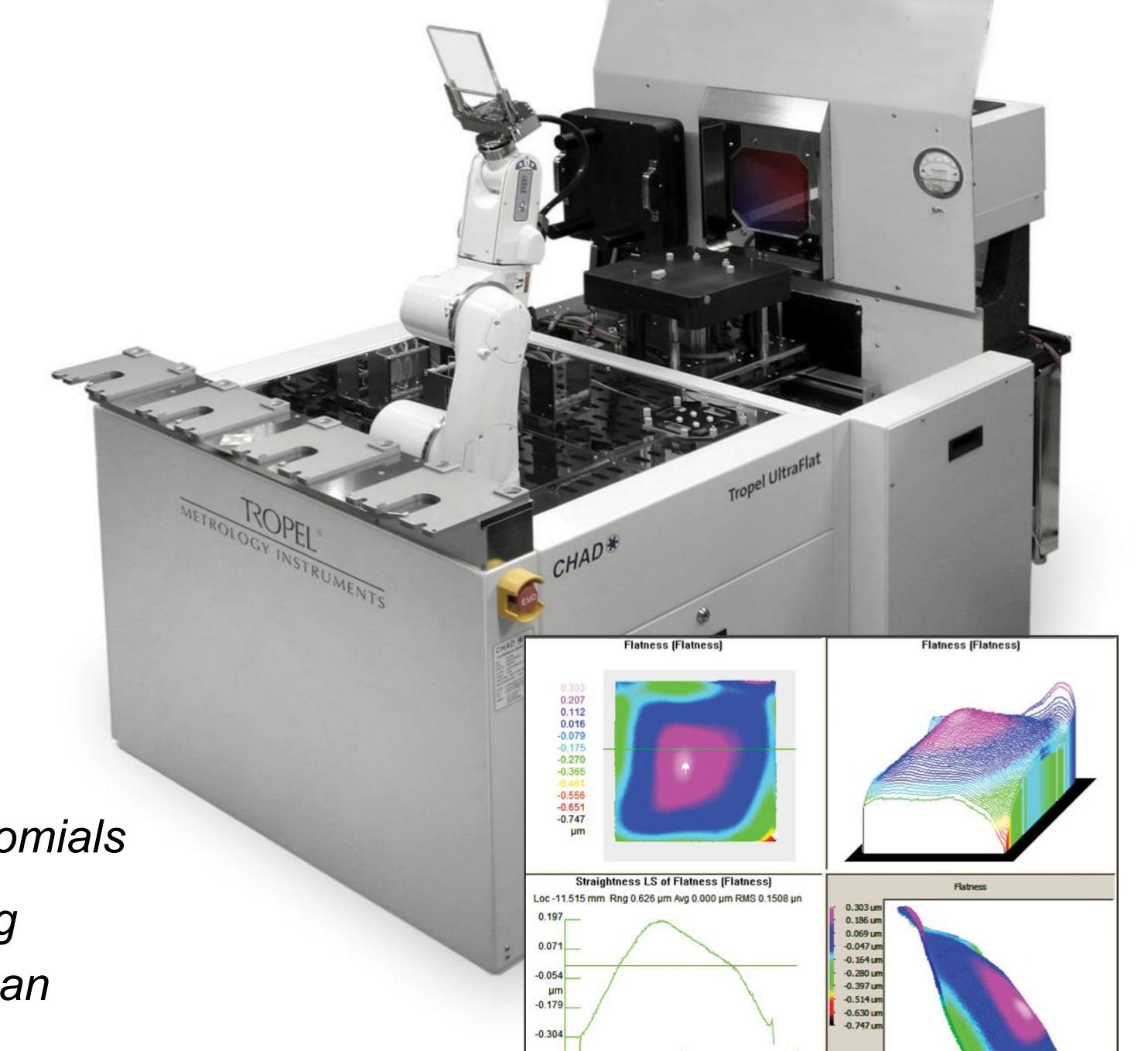


- Ground
- Lapped
- Honed
- Super-finished
- Polished
- Metals
- Polymers
- Ceramics
- Composites
- Glass
- many others
- Flatness
- Line profiles
- Surface profiles
- Spherical radius
- NIST traceable
 standard included

Tropel® UltraFlat™ System

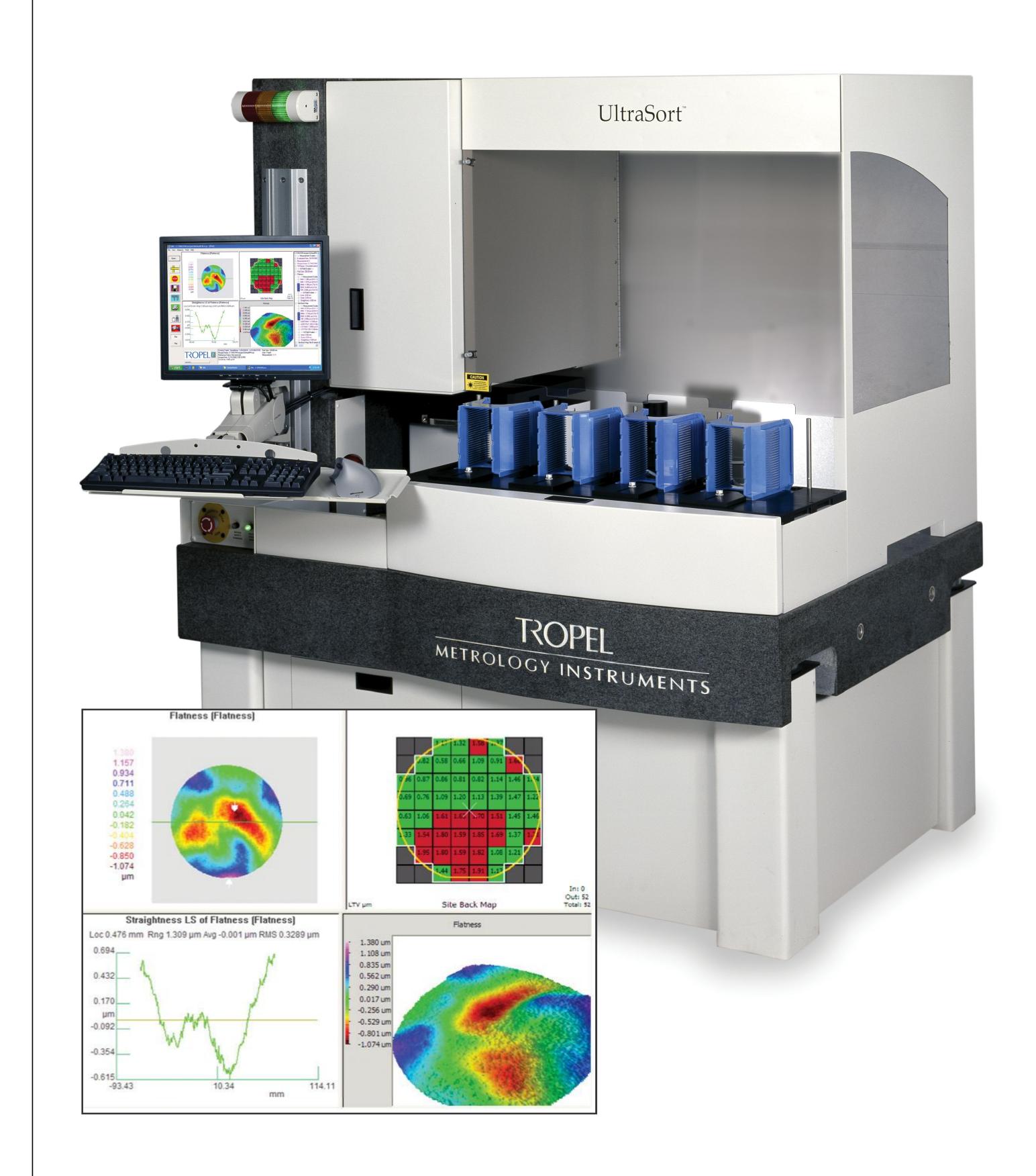
Photomask and photoblank sizes up to 150mm

- Photoblanks
- Photomasks
- Polished
- Coated
- Pre and post
 pellicle mount
 comparison
- 6025 & 5009 substrates
- Flatness
- Local slope
- Microwaviness
- Stress
- Legendre polynomials
- Robotic handling and Class 1 clean room options available



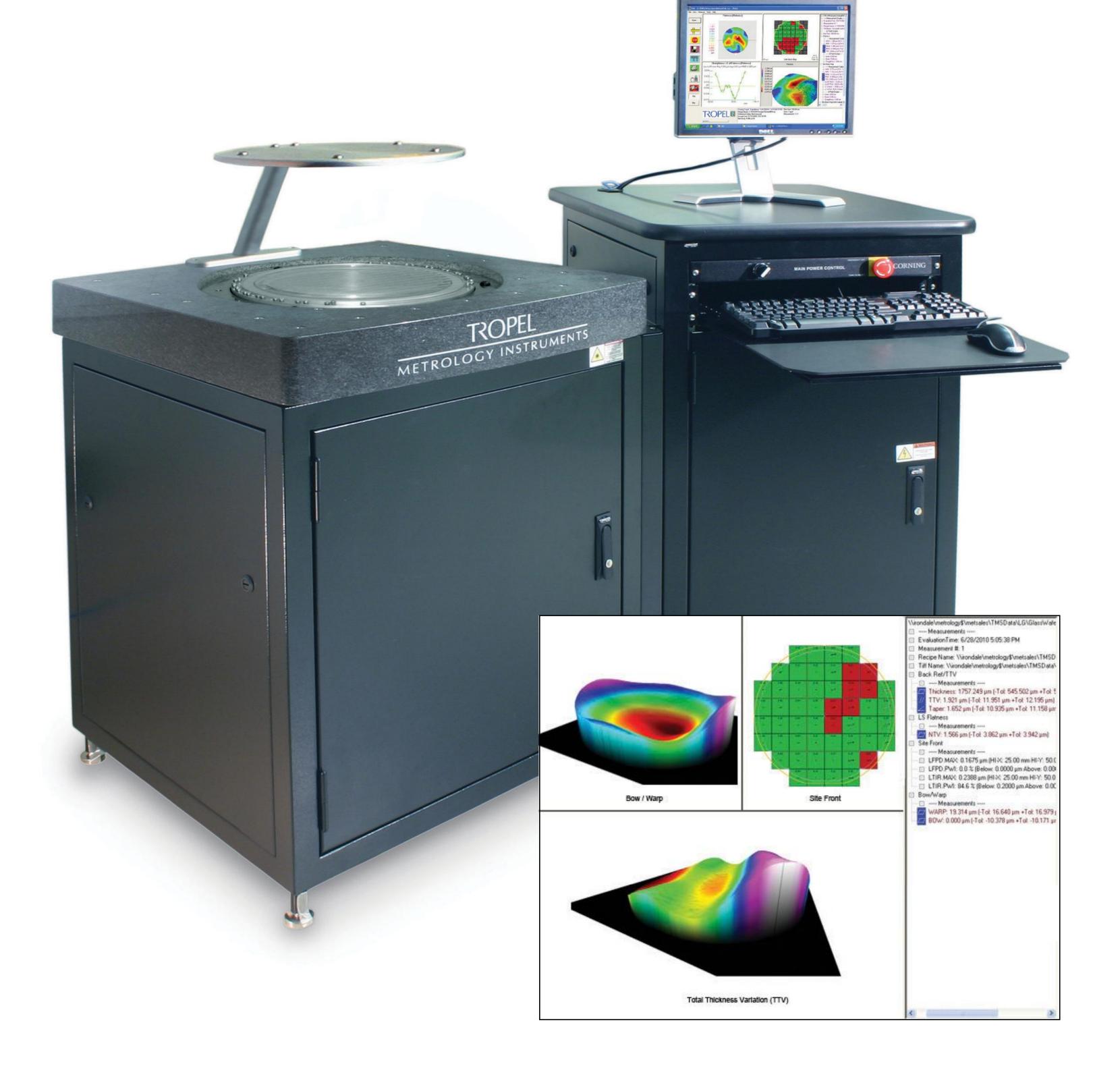
Tropel® UltraSort™ System

Wafer sizes from 50 mm to 200 mm



Sawn

- Ground
- Lapped
- Polished
- Silicon
- Silicon Carbide
- Gallium Arsenide
- Gallium Nitride
- Gallium Phosphide
- Sapphire
- Germanium
- many others
- Wafer Parameters
- Bow/Warp
- Sag/SORI
- GF3R (TIR) / GF3D (FPD)
- GBIR (TTV) / GFLR (NTV)
- GFLD (NTD)
- Site Parameters
- SBIR (LTV) / SBID (LDOF)
- SF3R, SFLR, SFQR (LTIR)
- SF3D, SFLD, SFQD (LFPD)



Tropel® FlatMaster® MSP-300 Wafer

Wafer sizes up to 300 mm